

In the Claims:

Please amend Claim 3 as indicted below. The status of all claims is as follows:

1-2. (Cancelled)

3. (Currently Amended) A method for repairing a defect in a display having pixel regions formed on a substrate, comprising the step of:

forming a bypass for a broken portion of a gate bus line making an electrical path through ~~by separating or connecting said gate bus line from or to~~ at least two of the following: a drain electrode, a source electrode of a TFT, a pixel electrode, and a storage capacitor bus line, which is formed with an insulation film interposed therebetween, said bypass being formed through local irradiation with a laser beam, thereby allowing said broken portion to be repaired by sacrificing regular use of an associated pixel.

4-5. (Cancelled)

6. (Previously presented) A method for repairing a defect in a display having pixel regions formed on a substrate, comprising the step of:

forming a bypass for a broken portion of a gate bus line by forming an alternate conductive path through a pixel electrode and a source electrode, whereby regular use of an associated pixel is sacrificed.

7. (Previously presented) The method according to Claim 6, further comprising the steps of:

creating a first electrically isolated line on a portion of a storage capacitor bus line, wherein said storage capacitor bus line is adjacent to said gate bus line, and further wherein said storage capacitor bus line is separated from said gate bus line by said pixel being sacrificed;

creating a second electrically isolated line on a portion of a drain bus line; and

forming said bypass by using local irradiation with a laser beam, said bypass consisting of a conductive path that includes a first edge of said broken gate bus line, said source electrode, said pixel being sacrificed, said first electrically isolated line, said second electrically isolated line, and a second edge of said broken gate bus line.

8. (Previously presented) The method according to Claim 7, wherein said conductive path also includes a drain electrode that is positioned adjacent said second edge of said broken gate bus line.

9-12. (Cancelled)

13. (Previously presented) A method for repairing a defect in a display having pixel regions formed on a substrate, comprising the step of:

forming a bypass for a broken portion of a gate bus line by making a conductive path that electrically connects said gate bus line to a pixel electrode and a storage capacitor bus line through local irradiation with a laser beam, thereby allowing said broken portion to be repaired by sacrificing regular use of an associated pixel.

14. (Previously presented) A method for repairing a defect in a display having pixel regions formed on a substrate, comprising the step of:

forming a bypass for a broken portion of a gate bus line by making a conductive path that electrically connects said gate bus line to a source electrode of a TFT and a pixel electrode through local irradiation with a laser beam, thereby allowing said broken portion to be repaired by sacrificing regular use of an associated pixel.

15. (Previously presented) A method for repairing a defect in a display having pixel regions formed on a substrate, comprising the step of:

forming a bypass for a broken portion of a gate bus line by making a conductive path that electrically connects said gate bus line to a pixel electrode and a drain

bus line through local irradiation with a laser beam, thereby allowing said broken portion to be repaired by sacrificing regular use of an associated pixel.